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## What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

## Applications of "[Embedded - Microcontrollers](#)"

### Details

Product Status	Last Time Buy
Core Processor	R8C
Core Size	16-Bit
Speed	20MHz
Connectivity	I <sup>2</sup> C, LINbus, SIO, SSU, UART/USART, USB
Peripherals	POR, PWM, Voltage Detect, WDT
Number of I/O	30
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	8K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 5.5V
Data Converters	-
Oscillator Type	Internal
Operating Temperature	-20°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	40-WFQFN Exposed Pad
Supplier Device Package	40-HWQFN (6x6)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f213m8unnp-w0">https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f213m8unnp-w0</a>

## 1.2 Product List

Tables 1.4 and 1.5 list Product List for Each Group. Figures 1.1 and 1.2 show a Part Number, Memory Size, and Package of Each Group.

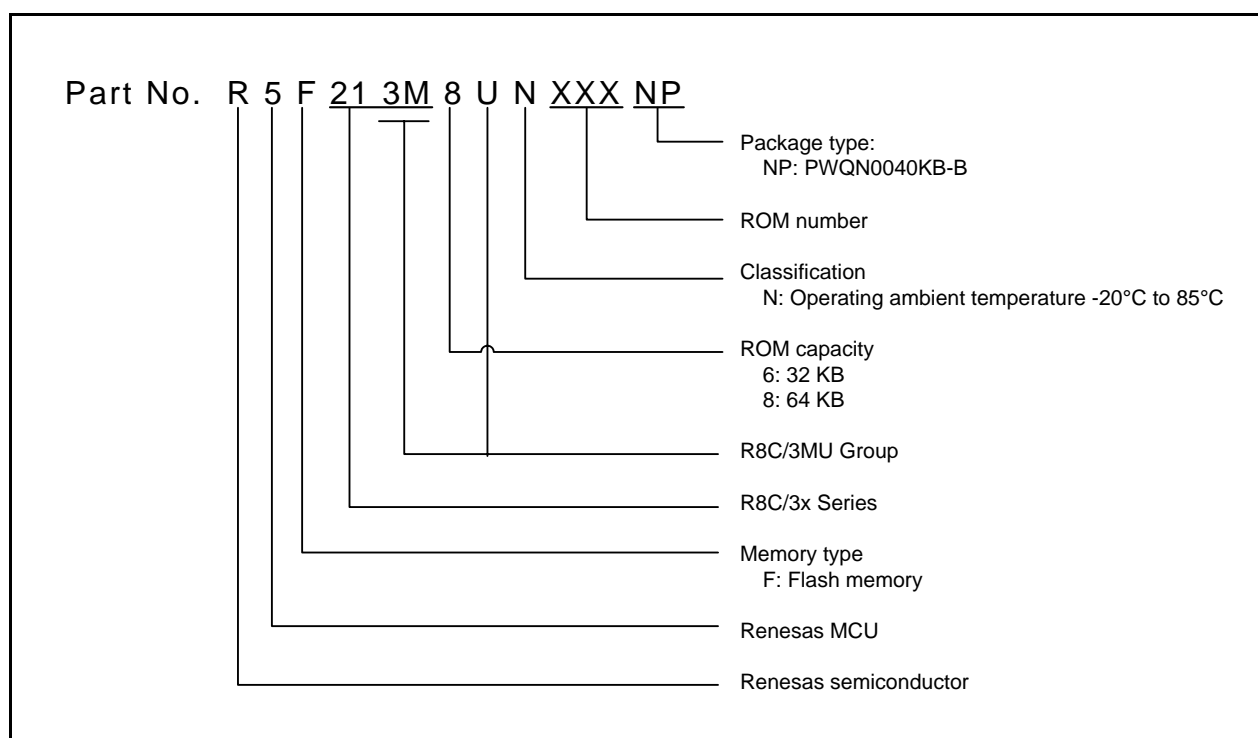
**Table 1.4 Product List for R8C/3MU Group**

**Current of Jun 2011**

Part No.	ROM Capacity		RAM Capacity	Package Type	Remarks	
	Program ROM	Data flash				
R5F213M6UNNP	32 Kbytes	1 Kbyte × 4	4 Kbytes	PWQN0040KB-B	N version	
R5F213M8UNNP	64 Kbytes	1 Kbyte × 4	8 Kbytes	PWQN0040KB-B		
R5F213M6UNXXXNP	32 Kbytes	1 Kbyte × 4	4 Kbytes	PWQN0040KB-B	N version	Factory programming product <sup>(1)</sup>
R5F213M8UNXXXNP	64 Kbytes	1 Kbyte × 4	8 Kbytes	PWQN0040KB-B		

Note:

1. The user ROM is programmed before shipment.



**Figure 1.1 Part Number, Memory Size, and Package of R8C/3MU Group**

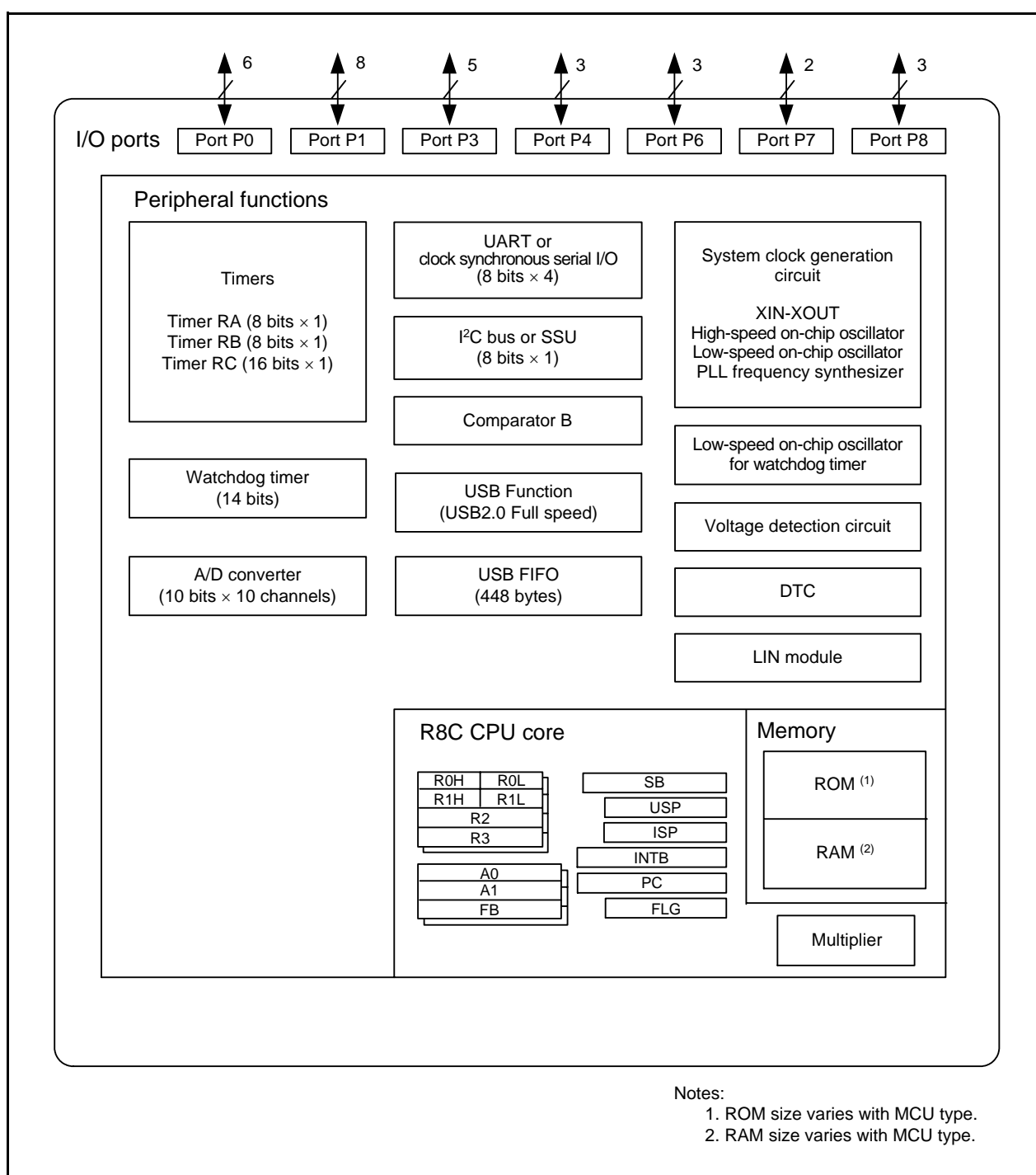
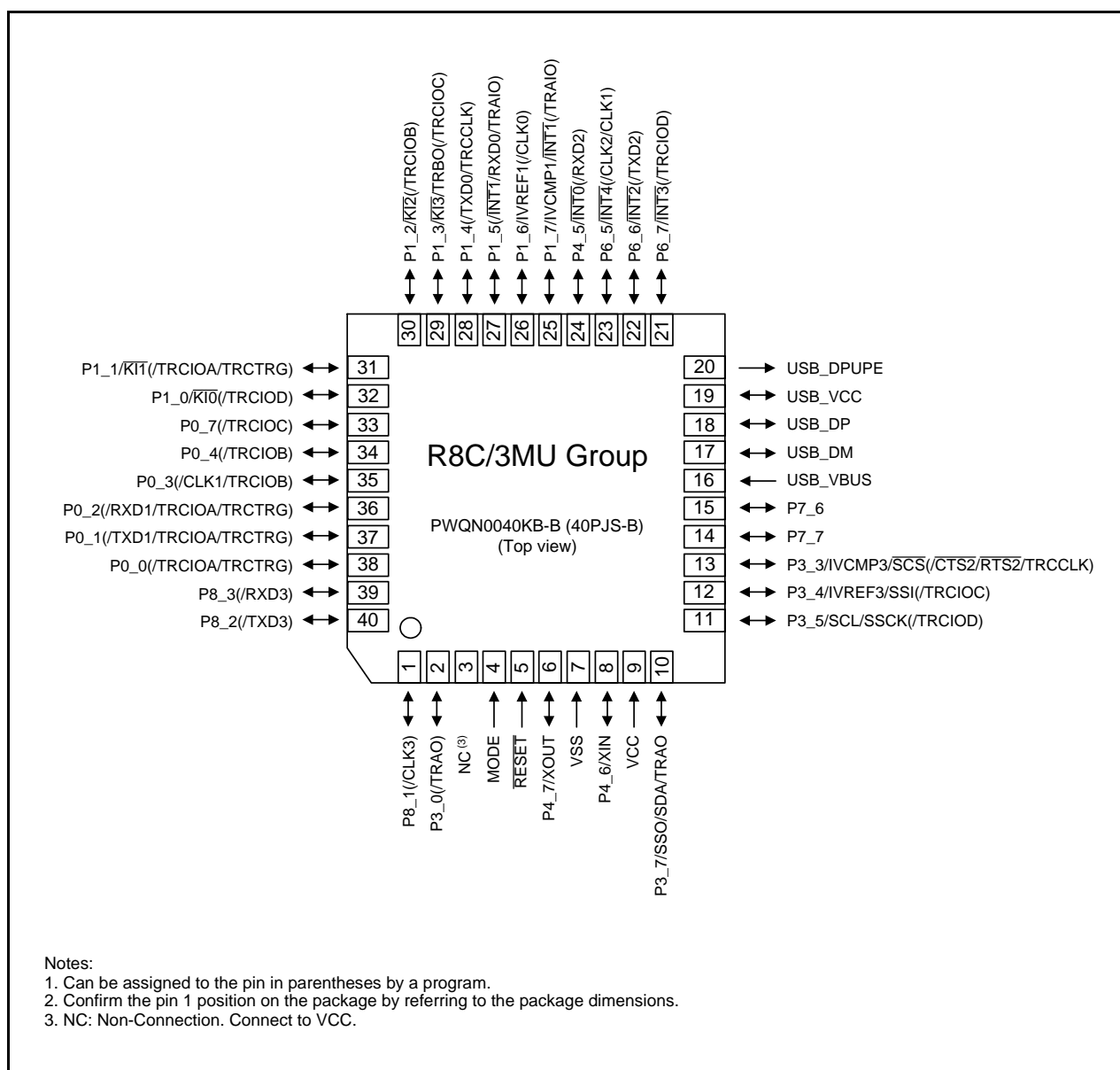


Figure 1.4 Block Diagram of R8C/3MK Group

## 1.4 Pin Assignment

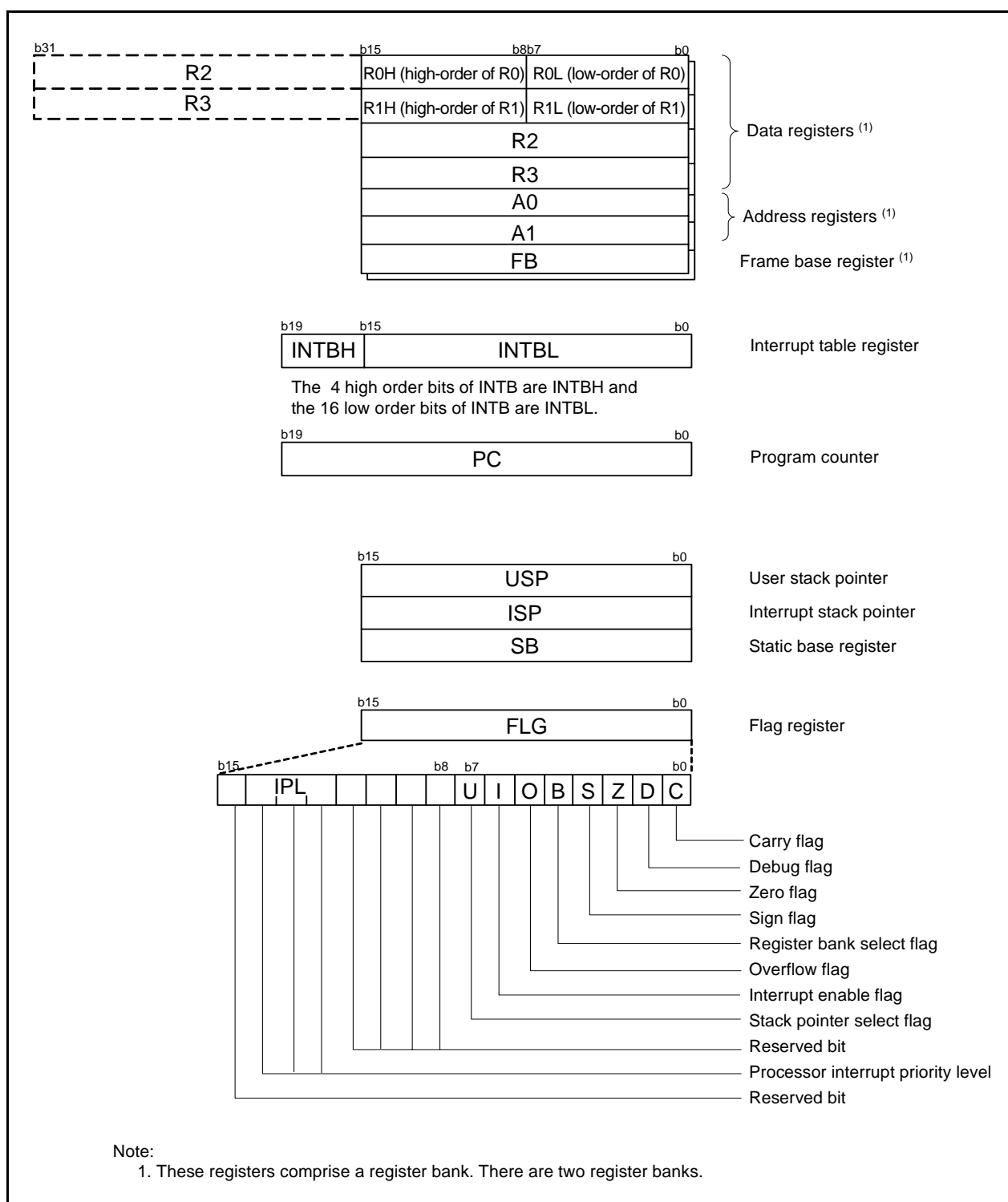
Figures 1.5 and 1.6 show Pin Assignment (Top View) of Each Group. Table 1.6 outlines the Pin Name Information by Pin Number.



**Figure 1.5 Pin Assignment (Top View) of R8C/3MU Group**

## 2. Central Processing Unit (CPU)

Figure 2.1 shows the CPU Registers. The CPU contains 13 registers. R0, R1, R2, R3, A0, A1, and FB configure a register bank. There are two sets of register bank.



**Figure 2.1 CPU Registers**

## 4. Special Function Registers (SFRs)

An SFR (special function register) is a control register for a peripheral function. Tables 4.1 to 4.15 list the special function registers. Table 4.16 lists the ID Code Areas and Option Function Select Area.

**Table 4.1 SFR Information (1) (1)**

Address	Register	Symbol	After Reset
0000h			
0001h			
0002h			
0003h			
0004h	Processor Mode Register 0	PM0	00h
0005h	Processor Mode Register 1	PM1	00h
0006h	System Clock Control Register 0	CM0	00101000b
0007h	System Clock Control Register 1	CM1	00100000b
0008h	Module Standby Control Register	MSTCR	00h
0009h	System Clock Control Register 3	CM3	00h
000Ah	Protect Register	PRCR	00h
000Bh	Reset Source Determination Register	RSTFR	0XXXXXXb (2)
000Ch	Oscillation Stop Detection Register	OCD	00000100b
000Dh	Watchdog Timer Reset Register	WDTR	XXh
000Eh	Watchdog Timer Start Register	WDTs	XXh
000Fh	Watchdog Timer Control Register	WDTC	00111111b
0010h			
0011h			
0012h			
0013h			
0014h			
0015h	High-Speed On-Chip Oscillator Control Register 7	FRA7	When shipping
0016h			
0017h			
0018h			
0019h			
001Ah			
001Bh			
001Ch	Count Source Protection Mode Register	CSPR	00h 10000000b (3)
001Dh			
001Eh			
001Fh			
0020h			
0021h			
0022h			
0023h	High-Speed On-Chip Oscillator Control Register 0	FRA0	00h
0024h	High-Speed On-Chip Oscillator Control Register 1	FRA1	When shipping
0025h	High-Speed On-Chip Oscillator Control Register 2	FRA2	00h
0026h	On-Chip Reference Voltage Control Register	OCVREFCR	00h
0027h			
0028h	Clock Prescaler Reset Flag	CPSRF	00h
0029h	High-Speed On-Chip Oscillator Control Register 4	FRA4	When shipping
002Ah	High-Speed On-Chip Oscillator Control Register 5	FRA5	When shipping
002Bh	High-Speed On-Chip Oscillator Control Register 6	FRA6	When shipping
002Ch			
002Dh			
002Eh			
002Fh	High-Speed On-Chip Oscillator Control Register 3	FRA3	When shipping
0030h	Voltage Monitor Circuit Control Register	CMPA	00h
0031h	Voltage Monitor Circuit Edge Select Register	VCAC	00h
0032h			
0033h	Voltage Detect Register 1	VCA1	00001000b
0034h	Voltage Detect Register 2	VCA2	00h (4) 00100000b (5)
0035h			
0036h	Voltage Detection 1 Level Select Register	VD1LS	00000111b
0037h			
0038h	Voltage Monitor 0 Circuit Control Register	VW0C	1100X010b (4) 1100X011b (5)
0039h	Voltage Monitor 1 Circuit Control Register	VW1C	10001010b

X: Undefined

Notes:

1. The blank areas are reserved and cannot be accessed by users.
2. The CWR bit in the RSTFR register is set to 0 after power-on and voltage monitor 0 reset. Hardware reset, software reset, or watchdog timer reset does not affect this bit.
3. The CSPROINI bit in the OFS register is set to 0.
4. The LVDAS bit in the OFS register is set to 1.
5. The LVDAS bit in the OFS register is set to 0.

**Table 4.7 SFR Information (7) <sup>(1)</sup>**

Address	Register	Symbol	After Reset
0180h	Timer RA Pin Select Register	TRASR	00h
0181h	Timer RC Pin Select Register	TRBRCR	00h
0182h	Timer RC Pin Select Register 0	TRCPSR0	00h
0183h	Timer RC Pin Select Register 1	TRCPSR1	00h
0184h			
0185h			
0186h			
0187h			
0188h	UART0 Pin Select Register	U0SR	00h
0189h	UART1 Pin Select Register	U1SR	00h
018Ah	UART2 Pin Select Register 0	U2SR0	00h
018Bh	UART2 Pin Select Register 1	U2SR1	00h
018Ch	SSU/IIC Pin Select Register	SSUIICSR	00h
018Dh			
018Eh	INT Interrupt Input Pin Select Register	INTSR	00h
018Fh	I/O Function Pin Select Register	PINSR	00h
0190h			
0191h			
0192h			
0193h	SS Bit Counter Register	SSBR	11111000b
0194h	SS Transmit Data Register L / IIC bus Transmit Data Register <sup>(2)</sup>	SSTDRL / ICDRT	FFh
0195h	SS Transmit Data Register H <sup>(2)</sup>	SSTDRLH	FFh
0196h	SS Receive Data Register L / IIC bus Receive Data Register <sup>(2)</sup>	SSRDL / ICDRL	FFh
0197h	SS Receive Data Register H <sup>(2)</sup>	SSRDLH	FFh
0198h	SS Control Register H / IIC bus Control Register 1 <sup>(2)</sup>	SSCRH / ICCR1	00h
0199h	SS Control Register L / IIC bus Control Register 2 <sup>(2)</sup>	SSCRL / ICCR2	01111101b
019Ah	SS Mode Register / IIC bus Mode Register <sup>(2)</sup>	SSMR / ICMR	00010000b / 00011000b
019Bh	SS Enable Register / IIC bus Interrupt Enable Register <sup>(2)</sup>	SSER / ICIE	00h
019Ch	SS Status Register / IIC bus Status Register <sup>(2)</sup>	SSSR / ICSR	00h / 0000X000b
019Dh	SS Mode Register 2 / Slave Address Register <sup>(2)</sup>	SSMR2 / SAR	00h
019Eh			
019Fh			
01A0h			
01A1h			
01A2h			
01A3h			
01A4h			
01A5h			
01A6h			
01A7h			
01A8h			
01A9h			
01AAh			
01ABh			
01ACH			
01ADh			
01AEh			
01AFh			
01B0h			
01B1h			
01B2h	Flash Memory Status Register	FST	10000X00b
01B3h			
01B4h	Flash Memory Control Register 0	FMR0	00h
01B5h	Flash Memory Control Register 1	FMR1	00h
01B6h	Flash Memory Control Register 2	FMR2	00h
01B7h			
01B8h			
01B9h			
01BAh			
01BBh			
01BCh			
01BDh			
01BEh			
01BFh			

X: Undefined

Notes:

1. The blank areas are reserved and cannot be accessed by users.
2. Selectable by the IICSEL bit in the SSUIICSR register.

**Table 4.8 SFR Information (8) (1)**

Address	Register	Symbol	After Reset
01C0h	Address Match Interrupt Register 0	RMAD0	XXh
01C1h			XXh
01C2h			0000XXXXb
01C3h	Address Match Interrupt Enable Register 0	AIER0	00h
01C4h	Address Match Interrupt Register 1	RMAD1	XXh
01C5h			XXh
01C6h			0000XXXXb
01C7h	Address Match Interrupt Enable Register 1	AIER1	00h
01C8h			
01C9h			
01CAh			
01CBh			
01CCh			
01CDh			
01CEh			
01CFh			
01D0h			
01D1h			
01D2h			
01D3h			
01D4h			
01D5h			
01D6h			
01D7h			
01D8h			
01D9h			
01DAh			
01DBh			
01DCh			
01DDh			
01DEh			
01DFh			
01E0h	Pull-Up Control Register 0	PUR0	00h
01E1h	Pull-Up Control Register 1	PUR1	00h
01E2h	Pull-Up Control Register 2	PUR2	00h
01E3h			
01E4h			
01E5h			
01E6h			
01E7h			
01E8h			
01E9h			
01EAh			
01EBh			
01ECh			
01EDh			
01EEh			
01EFh			
01F0h	Port P1 Drive Capacity Control Register	P1DRR	00h
01F1h			
01F2h	Drive Capacity Control Register 0	DRR0	00h
01F3h	Drive Capacity Control Register 1	DRR1	00h
01F4h	Drive Capacity Control Register 2	DRR2	00h
01F5h	Input Threshold Control Register 0	VLT0	00h
01F6h	Input Threshold Control Register 1	VLT1	00h
01F7h	Input Threshold Control Register 2	VLT2	00h
01F8h	Comparator B Control Register 0	INTCMP	00h
01F9h			
01FAh	External Input Enable Register 0	INTEN	00h
01FBh	External Input Enable Register 1	INTEN1	00h
01FCh	INT Input Filter Select Register 0	INTF	00h
01FDh	INT Input Filter Select Register 1	INTF1	00h
01FEh	Key Input Enable Register 0	KIEN	00h
01FFh			

X: Undefined

Note:

1. The blank areas are reserved and cannot be accessed by users.



**Table 4.15 SFR Information (15) (1)**

Address	Register	Symbol	After Reset
2F00h	USB Module Control Register	USBMC	00X10000b
2F01h	PLL Control Register 0	PLC0	0010X000b
2F02h	PLL Control Register 1	PLC1	00001100b
2F03h	PLL Division Control Register	PLDIV	00001011b
2F04h			
2F05h			
2F06h			
2F07h			
2F08h			
2F09h			
2F0Ah			
2F0Bh			
2F0Ch			
2F0Dh			
2F0Eh			
2F0Fh			
2F10h	USB Pin Select Register 0	USBSR0	00h
2F11h			
2F12h	UART3 Pin Select Register	U3SR	00h
2F13h			
2F14h			
2F15h			
2F16h			
2F17h			
2F18h			
2F19h			
2F1Ah			
2F1Bh			
2F1Ch			
2F1Dh			
2F1Eh			
2F1Fh			
⋮			
2FFFh			

X: Undefined

Note:

1. The blank areas are reserved and cannot be accessed by users.

**Table 4.16 ID Code Areas and Option Function Select Area**

Address	Area Name	Symbol	After Reset
⋮			
FFDBh	Option Function Select Register 2	OFS2	(Note 1)
⋮			
FFDFh	ID1		(Note 2)
⋮			
FFE3h	ID2		(Note 2)
⋮			
FFEBh	ID3		(Note 2)
⋮			
FFEFh	ID4		(Note 2)
⋮			
FFF3h	ID5		(Note 2)
⋮			
FFF7h	ID6		(Note 2)
⋮			
FFFBh	ID7		(Note 2)
⋮			
FFFFh	Option Function Select Register	OFS	(Note 1)

Notes:

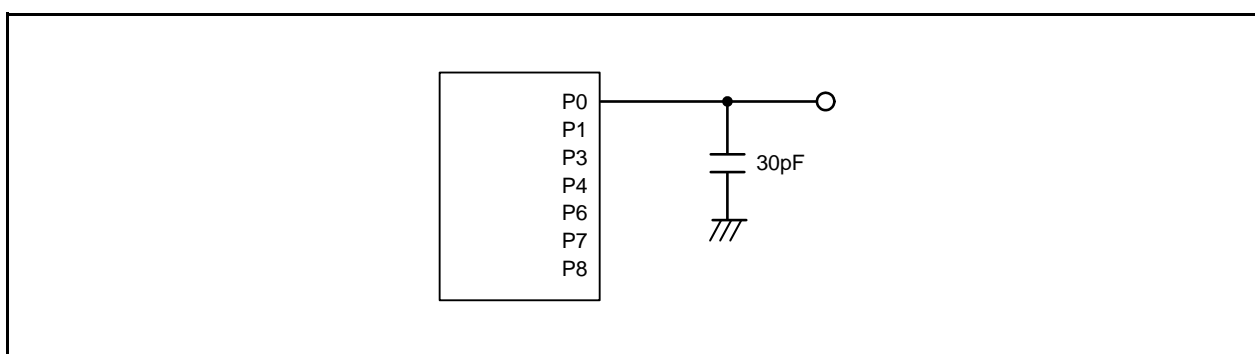
1. The option function select area is allocated in the flash memory, not in the SFRs. Set appropriate values as ROM data by a program.  
Do not write additions to the option function select area. If the block including the option function select area is erased, the option function select area is set to FFh.  
When blank products are shipped, the option function select area is set to FFh. It is set to the written value after written by the user.  
When factory-programming products are shipped, the value of the option function select area is the value programmed by the user.
2. The ID code areas are allocated in the flash memory, not in the SFRs. Set appropriate values as ROM data by a program.  
Do not write additions to the ID code areas. If the block including the ID code areas is erased, the ID code areas are set to FFh.  
When blank products are shipped, the ID code areas are set to FFh. They are set to the written value after written by the user.  
When factory-programming products are shipped, the value of the ID code areas is the value programmed by the user.

**Table 5.2 Recommended Operating Conditions (1)**

Symbol	Parameter				Conditions	Standard			Unit	
						Min.	Typ.	Max.		
Vcc	Supply voltage	When USB function is used				3.0	5.0	5.5	V	
		When USB function is not used				1.8	5.0	5.5	V	
UVcc	USB Supply Voltage (When UVCC pin is input)	When USB function is used			Vcc = 3.0 to 3.6 V	—	Vcc (4)	—	V	
		When USB function is not used			Vcc = 1.8 to 5.5 V	—	Vcc (4)	—	V	
Vss	Supply voltage					—	0	—	V	
VIH	Input “H” voltage	Other than CMOS input					0.8 Vcc	—	Vcc	V
		CMOS input	Input level switching function (I/O port)	Input level selection: 0.35 Vcc	4.0 V ≤ Vcc ≤ 5.5 V	0.5 Vcc	—	Vcc	V	
					2.7 V ≤ Vcc < 4.0 V	0.55 Vcc	—	Vcc	V	
					1.8 V ≤ Vcc < 2.7 V	0.65 Vcc	—	Vcc	V	
				Input level selection: 0.5 Vcc	4.0 V ≤ Vcc ≤ 5.5 V	0.65 Vcc	—	Vcc	V	
					2.7 V ≤ Vcc < 4.0 V	0.7 Vcc	—	Vcc	V	
					1.8 V ≤ Vcc < 2.7 V	0.8 Vcc	—	Vcc	V	
				Input level selection: 0.7 Vcc	4.0 V ≤ Vcc ≤ 5.5 V	0.85 Vcc	—	Vcc	V	
					2.7 V ≤ Vcc < 4.0 V	0.85 Vcc	—	Vcc	V	
					1.8 V ≤ Vcc < 2.7 V	0.85 Vcc	—	Vcc	V	
	External clock input (XOUT)					1.2	—	Vcc	V	
VIL	Input “L” voltage	Other than CMOS input					0	—	0.2 Vcc	V
		CMOS input	Input level switching function (I/O port)	Input level selection: 0.35 Vcc	4.0 V ≤ Vcc ≤ 5.5 V	0	—	0.2 Vcc	V	
					2.7 V ≤ Vcc < 4.0 V	0	—	0.2 Vcc	V	
					1.8 V ≤ Vcc < 2.7 V	0	—	0.2 Vcc	V	
				Input level selection: 0.5 Vcc	4.0 V ≤ Vcc ≤ 5.5 V	0	—	0.4 Vcc	V	
					2.7 V ≤ Vcc < 4.0 V	0	—	0.3 Vcc	V	
					1.8 V ≤ Vcc < 2.7 V	0	—	0.2 Vcc	V	
				Input level selection: 0.7 Vcc	4.0 V ≤ Vcc ≤ 5.5 V	0	—	0.55 Vcc	V	
					2.7 V ≤ Vcc < 4.0 V	0	—	0.45 Vcc	V	
					1.8 V ≤ Vcc < 2.7 V	0	—	0.35 Vcc	V	
	External clock input (XOUT)					0	—	0.4	V	
IOH(sum)	Peak sum output “H” current		Sum of all pins IOH(peak)			—	—	−160	mA	
IOH(sum)	Average sum output “H” current		Sum of all pins IOH(avg)			—	—	−80	mA	
IOH(peak)	Peak output “H” current		Drive capacity Low			—	—	−10	mA	
			Drive capacity High			—	—	−40	mA	
IOH(avg)	Average output “H” current		Drive capacity Low			—	—	−5	mA	
			Drive capacity High			—	—	−20	mA	
IoL(sum)	Peak sum output “L” current		Sum of all pins IoL(peak)			—	—	160	mA	
IoL(sum)	Average sum output “L” current		Sum of all pins IoL(avg)			—	—	80	mA	
IoL(peak)	Peak output “L” current		Drive capacity Low			—	—	10	mA	
			Drive capacity High			—	—	40	mA	
IoL(avg)	Average output “L” current		Drive capacity Low			—	—	5	mA	
			Drive capacity High			—	—	20	mA	
f(XIN)	XIN clock input oscillation frequency				2.7 V ≤ Vcc ≤ 5.5 V	—	—	20	MHz	
					1.8 V ≤ Vcc < 2.7 V	—	—	5	MHz	
fOCO40M	When used as the count source for timer RC (3)				2.7 V ≤ Vcc ≤ 5.5 V	32	—	40	MHz	
fOCO-F	fOCO-F frequency				2.7 V ≤ Vcc ≤ 5.5 V	—	—	20	MHz	
					1.8 V ≤ Vcc < 2.7 V	—	—	5	MHz	
—	System clock frequency				2.7 V ≤ Vcc ≤ 5.5 V	—	—	20	MHz	
					1.8 V ≤ Vcc < 2.7 V	—	—	5	MHz	
f(BCLK)	CPU clock frequency				2.7 V ≤ Vcc ≤ 5.5 V	—	—	20	MHz	
					1.8 V ≤ Vcc < 2.7 V	—	—	5	MHz	
tsu(PLL)	PLL frequency synthesizer stabilization wait time				4.0 V ≤ Vcc ≤ 5.5 V	—	—	2	ms	
					2.7 V ≤ Vcc < 4.0 V	—	—	3	ms	

Notes:

1. V<sub>CC</sub> = 1.8 to 5.5 V and T<sub>opr</sub> = −20 to 85 °C (N version), unless otherwise specified.
2. The average output current indicates the average value of current measured during 100 ms.
3. fOCO40M can be used as the count source for timer RC in the range of V<sub>CC</sub> = 2.7 to 5.5 V.
4. Connect V<sub>CC</sub> for the UV<sub>CC</sub> pin input.



**Figure 5.1** Ports P0, P1, P3, P4, P6, P7 and P8 Timing Measurement Circuit

**Table 5.3** Comparator B Electrical Characteristics

Symbol	Parameter	Condition	Standard			Unit
			Min.	Typ.	Max.	
$V_{ref}$	IVREF1, IVREF3 input reference voltage		0	—	$V_{CC} - 1.4$	V
$V_I$	IVCMP1, IVCMP3 input voltage		-0.3	—	$V_{CC} + 0.3$	V
—	Offset		—	5	100	mV
$t_d$	Comparator output delay time <sup>(2)</sup>	$V_I = V_{ref} \pm 100$ mV	—	0.1	—	$\mu$ s
$I_{CMP}$	Comparator operating current	$V_{CC} = 5.0$ V	—	17.5	—	$\mu$ A

Notes:

1.  $V_{CC} = 2.7$  to  $5.5$  V and  $T_{opr} = -20$  to  $85$  °C (N version), unless otherwise specified.
2. When the digital filter is disabled.

**Table 5.11 High-speed On-Chip Oscillator Circuit Electrical Characteristics**

Symbol	Parameter	Condition	Standard			Unit
			Min.	Typ.	Max.	
—	High-speed on-chip oscillator frequency after reset	$V_{CC} = 1.8 \text{ V to } 5.5 \text{ V}$	36.0	40	44.0	MHz
—	High-speed on-chip oscillator frequency when the FRA4 register correction value is written into the FRA1 register and the FRA5 register correction value into the FRA3 register <sup>(2)</sup>	$V_{CC} = 1.8 \text{ V to } 5.5 \text{ V}$	33.178	36.864	40.550	MHz
—	High-speed on-chip oscillator frequency when the FRA6 register correction value is written into the FRA1 register and the FRA7 register correction value into the FRA3 register	$V_{CC} = 1.8 \text{ V to } 5.5 \text{ V}$	28.8	32	35.2	MHz
—	Oscillation stability time	$V_{CC} = 5.0 \text{ V}$ , $T_{opr} = 25 \text{ }^{\circ}\text{C}$	—	0.5	3	ms
—	Self power consumption at oscillation	$V_{CC} = 5.0 \text{ V}$ , $T_{opr} = 25 \text{ }^{\circ}\text{C}$	—	400	—	$\mu\text{A}$

Notes:

1.  $V_{CC} = 1.8$  to  $5.5 \text{ V}$  and  $T_{opr} = -20$  to  $85 \text{ }^{\circ}\text{C}$  (N version), unless otherwise specified.
2. This enables the setting errors of bit rates such as 9600 bps and 38400 bps to be 0% when the serial interface is used in UART mode.

**Table 5.12 Low-speed On-Chip Oscillator Circuit Electrical Characteristics**

Symbol	Parameter	Condition	Standard			Unit
			Min.	Typ.	Max.	
fOCO-S	Low-speed on-chip oscillator frequency		60	125	250	kHz
—	Oscillation stability time	$V_{CC} = 5.0 \text{ V}$ , $T_{opr} = 25 \text{ }^{\circ}\text{C}$	—	30	100	$\mu\text{s}$
—	Self power consumption at oscillation	$V_{CC} = 5.0 \text{ V}$ , $T_{opr} = 25 \text{ }^{\circ}\text{C}$	—	2	—	$\mu\text{A}$

Note:

1.  $V_{CC} = 1.8$  to  $5.5 \text{ V}$  and  $T_{opr} = -20$  to  $85 \text{ }^{\circ}\text{C}$  (N version), unless otherwise specified.

**Table 5.13 Power Supply Circuit Timing Characteristics**

Symbol	Parameter	Condition	Standard			Unit
			Min.	Typ.	Max.	
t <sub>d(P-R)</sub>	Time for internal power supply stabilization during power-on <sup>(2)</sup>		—	—	2,000	$\mu\text{s}$

Notes:

1. The measurement condition is  $V_{CC} = 1.8$  to  $5.5 \text{ V}$  and  $T_{opr} = 25 \text{ }^{\circ}\text{C}$ .
2. Waiting time until the internal power supply generation circuit stabilizes during power-on.

**Table 5.16 Electrical Characteristics (1) [ $4.2\text{ V} \leq V_{CC} \leq 5.5\text{ V}$ ]**

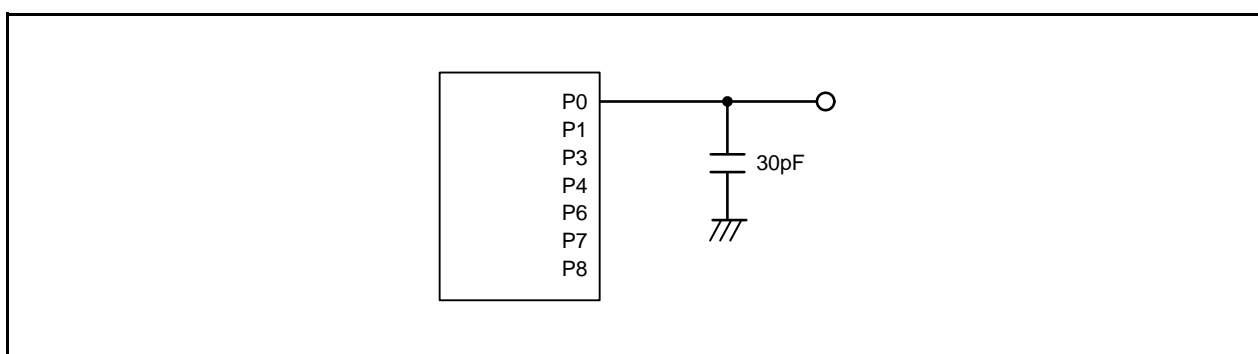
Symbol	Parameter		Condition		Standard			Unit
					Min.	Typ.	Max.	
V <sub>OH</sub>	Output "H" voltage	Other than XOUT	Drive capacity High $V_{CC} = 5\text{ V}$	I <sub>OH</sub> = -20 mA	V <sub>CC</sub> - 2.0	—	V <sub>CC</sub>	V
			Drive capacity Low $V_{CC} = 5\text{ V}$	I <sub>OH</sub> = -5 mA	V <sub>CC</sub> - 2.0	—	V <sub>CC</sub>	V
		XOUT	V <sub>CC</sub> = 5 V	I <sub>OH</sub> = -200 $\mu\text{A}$	1.0	—	V <sub>CC</sub>	V
V <sub>OL</sub>	Output "L" voltage	Other than XOUT	Drive capacity High $V_{CC} = 5\text{ V}$	I <sub>OL</sub> = 20 mA	—	—	2.0	V
			Drive capacity Low $V_{CC} = 5\text{ V}$	I <sub>OL</sub> = 5 mA	—	—	2.0	V
		XOUT	V <sub>CC</sub> = 5 V	I <sub>OL</sub> = 200 $\mu\text{A}$	—	—	0.5	V
V <sub>T+</sub> -V <sub>T-</sub>	Hysteresis	INT0, INT1, INT2, INT3, INT4, K10, K11, K12, K13, TRAIO, TRCIOA, TRCIOB, TRCIOC, TRCIOD, USB_VBUS, TRCTRG, TRCCLK, RXD0, RXD1, RXD2, RXD3, CLK0, CLK1, CLK2, CLK3, CTS2, SSI, SCL, SDA, SSO, SSCK, SCS			0.1	1.2	—	V
		RESET			0.1	1.2	—	V
I <sub>IH</sub>	Input "H" current		V <sub>I</sub> = 5 V, V <sub>CC</sub> = 5.0 V		—	—	5.0	$\mu\text{A}$
I <sub>IL</sub>	Input "L" current		V <sub>I</sub> = 0 V, V <sub>CC</sub> = 5.0 V		—	—	-5.0	$\mu\text{A}$
R <sub>PULLUP</sub>	Pull-up resistance		V <sub>I</sub> = 0 V, V <sub>CC</sub> = 5.0 V		25	50	100	k $\Omega$
R <sub>fXIN</sub>	Feedback resistance	XIN			—	0.3	—	M $\Omega$
V <sub>RAM</sub>	RAM hold voltage		During stop mode		1.8	—	—	V

Note:

1.  $4.2\text{ V} \leq V_{CC} \leq 5.5\text{ V}$ , T<sub>opr</sub> = -20 to 85 °C (N version), and f(XIN) = 20 MHz, unless otherwise specified.

**Table 5.29 Electrical Characteristics (6) [ $1.8\text{ V} \leq V_{CC} < 2.7\text{ V}$ ]**  
**( $T_{opr} = -20\text{ to }85\text{ }^{\circ}\text{C}$  (N version), unless otherwise specified.)**

Symbol	Parameter	Condition	Standard			Unit
			Min.	Typ.	Max.	
I <sub>CC</sub>	Power supply current ( $V_{CC} = 1.8\text{ to }2.7\text{ V}$ ) Single-chip mode, output pins are open, other pins are V <sub>SS</sub>	High-speed clock mode	—	2.2	—	mA
		XIN = 5 MHz (square wave) High-speed on-chip oscillator off Low-speed on-chip oscillator on = 125 kHz No division	—	0.8	—	mA
		XIN = 5 MHz (square wave) High-speed on-chip oscillator off Low-speed on-chip oscillator on = 125 kHz Divide-by-8	—	0.8	—	mA
		High-speed on-chip oscillator mode	—	2.5	10	mA
		XIN clock off High-speed on-chip oscillator on fOCO-F = 5 MHz Low-speed on-chip oscillator on = 125 kHz No division	—	1.7	—	mA
		XIN clock off High-speed on-chip oscillator on fOCO-F = 5 MHz Low-speed on-chip oscillator on = 125 kHz Divide-by-8	—	1.7	—	mA
		XIN clock off High-speed on-chip oscillator on fOCO-F = 4 MHz Low-speed on-chip oscillator on = 125 kHz Divide-by-16, MSTIIC=MSTTRC=1	—	1	—	mA
		Low-speed on-chip oscillator mode	—	90	300	μA
		Wait mode	—	15	90	μA
		XIN clock off High-speed on-chip oscillator off Low-speed on-chip oscillator on = 125 kHz While a WAIT instruction is executed Peripheral clock operation VCA27 = VCA26 = VCA25 = 0, VCA20 = 1	—	4	80	μA
		XIN clock off High-speed on-chip oscillator off Low-speed on-chip oscillator on = 125 kHz While a WAIT instruction is executed Peripheral clock off VCA27 = VCA26 = VCA25 = 0, VCA20 = 1	—	3.5	—	μA
		Stop mode	—	2.0	5	μA
		XIN clock off, $T_{opr} = 25\text{ }^{\circ}\text{C}$ High-speed on-chip oscillator off Low-speed on-chip oscillator off CM10 = 1 Peripheral clock off VCA27 = VCA26 = VCA25 = 0	—	15	—	μA
		XIN clock off, $T_{opr} = 85\text{ }^{\circ}\text{C}$ High-speed on-chip oscillator off Low-speed on-chip oscillator off CM10 = 1 Peripheral clock off VCA27 = VCA26 = VCA25 = 0	—	15	—	μA



**Figure 5.22** Ports P0, P1, P3, P4, P6, P7 and P8 Timing Measurement Circuit

Table 5.36 A/D Converter Characteristics

Symbol	Parameter		Conditions		Standard			Unit
					Min.	Typ.	Max.	
—	Resolution		V <sub>ref</sub> = AV <sub>CC</sub>		—	—	10	Bit
—	Absolute accuracy	10-bit mode	V <sub>ref</sub> = AV <sub>CC</sub> = 5.0 V	AN0, AN3 to AN7 input, AN8 to AN11 input	—	—	±3	LSB
			V <sub>ref</sub> = AV <sub>CC</sub> = 3.3 V	AN0, AN3 to AN7 input, AN8 to AN11 input	—	—	±5	LSB
			V <sub>ref</sub> = AV <sub>CC</sub> = 3.0 V	AN0, AN3 to AN7 input, AN8 to AN11 input	—	—	±5	LSB
			V <sub>ref</sub> = AV <sub>CC</sub> = 2.2 V	AN0, AN3 to AN7 input, AN8 to AN11 input	—	—	±5	LSB
		8-bit mode	V <sub>ref</sub> = AV <sub>CC</sub> = 5.0 V	AN0, AN3 to AN7 input, AN8 to AN11 input	—	—	±2	LSB
			V <sub>ref</sub> = AV <sub>CC</sub> = 3.3 V	AN0, AN3 to AN7 input, AN8 to AN11 input	—	—	±2	LSB
			V <sub>ref</sub> = AV <sub>CC</sub> = 3.0 V	AN0, AN3 to AN7 input, AN8 to AN11 input	—	—	±2	LSB
			V <sub>ref</sub> = AV <sub>CC</sub> = 2.2 V	AN0, AN3 to AN7 input, AN8 to AN11 input	—	—	±2	LSB
φAD	A/D conversion clock		4.0 V ≤ V <sub>ref</sub> = AV <sub>CC</sub> ≤ 5.5 V <sup>(2)</sup>		2	—	20	MHz
			3.2 V ≤ V <sub>ref</sub> = AV <sub>CC</sub> ≤ 5.5 V <sup>(2)</sup>		2	—	16	MHz
			2.7 V ≤ V <sub>ref</sub> = AV <sub>CC</sub> ≤ 5.5 V <sup>(2)</sup>		2	—	10	MHz
			2.2 V ≤ V <sub>ref</sub> = AV <sub>CC</sub> ≤ 5.5 V <sup>(2)</sup>		2	—	5	MHz
—	Tolerance level impedance				—	3	—	kΩ
tCONV	Conversion time	10-bit mode	V <sub>ref</sub> = AV <sub>CC</sub> = 5.0 V, φAD = 20 MHz		2.2	—	—	μs
		8-bit mode	V <sub>ref</sub> = AV <sub>CC</sub> = 5.0 V, φAD = 20 MHz		2.2	—	—	μs
tsAMP	Sampling time		φAD = 20 MHz		0.8	—	—	μs
I <sub>Vref</sub>	V <sub>ref</sub> current		V <sub>CC</sub> = 5.0 V, XIN = f1 = φAD = 20 MHz		—	45	—	μA
V <sub>ref</sub>	Reference voltage				2.2	—	AV <sub>CC</sub>	V
V <sub>IA</sub>	Analog input voltage <sup>(3)</sup>				0	—	V <sub>ref</sub>	V
OCVREF	On-chip reference voltage		2 MHz ≤ φAD ≤ 4 MHz		1.19	1.34	1.49	V

Notes:

1.  $V_{CC}/AV_{CC} = V_{ref} = 2.2$  to  $5.5\text{ V}$ ,  $V_{SS} = 0\text{ V}$ , and  $T_{opr} = -20$  to  $85\text{ }^{\circ}\text{C}$  (N version), unless otherwise specified.
2. The A/D conversion result will be undefined in wait mode, stop mode, when the flash memory stops, and in low-current-consumption mode. Do not perform A/D conversion in these states or transition to these states during A/D conversion.
3. When the analog input voltage is over the reference voltage, the A/D conversion result will be 3FFh in 10-bit mode and FFh in 8-bit mode.



**Table 5.39 Flash Memory (Program ROM) Electrical Characteristics**

Symbol	Parameter	Conditions	Standard			Unit
			Min.	Typ.	Max.	
—	Program/erase endurance <sup>(2)</sup>		1,000 <sup>(3)</sup>	—	—	times
—	Byte program time		—	80	500	μs
—	Block erase time		—	0.3	—	s
t <sub>d</sub> (SR-SUS)	Time delay from suspend request until suspend		—	—	5 + CPU clock × 3 cycles	ms
—	Interval from erase start/restart until following suspend request		0	—	—	μs
—	Time from suspend until erase restart		—	—	30 + CPU clock × 1 cycle	μs
t <sub>d</sub> (CMDRST-READY)	Time from when command is forcibly stopped until reading is enabled		—	—	30 + CPU clock × 1 cycle	μs
—	Program, erase voltage		2.7	—	5.5	V
—	Read voltage		1.8	—	5.5	V
—	Program, erase temperature		0	—	60	°C
—	Data hold time <sup>(7)</sup>	Ambient temperature = 55 °C	20	—	—	year

**Notes:**

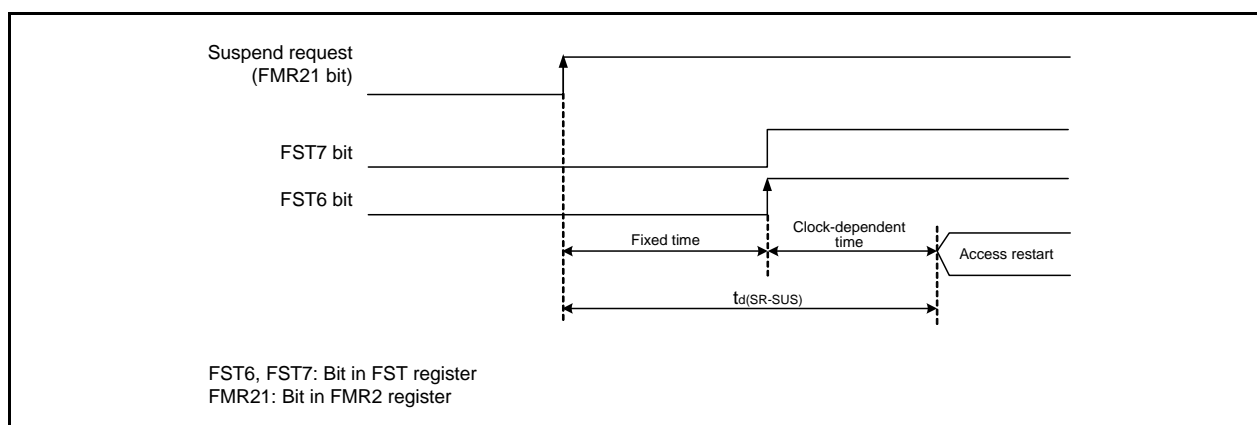
1. V<sub>CC</sub> = 2.7 to 5.5 V and T<sub>opr</sub> = 0 to 60 °C, unless otherwise specified.
2. Definition of programming/erasure endurance  
The programming and erasure endurance is defined on a per-block basis.  
If the programming and erasure endurance is n (n = 1,000), each block can be erased n times. For example, if 1,024 1-byte writes are performed to different addresses in block A, a 1 Kbyte block, and then the block is erased, the programming/erasure endurance still stands at one. However, the same address must not be programmed more than once per erase operation (overwriting prohibited).
3. Endurance to guarantee all electrical characteristics after program and erase. (1 to Min. value can be guaranteed.)
4. In a system that executes multiple programming operations, the actual erasure count can be reduced by writing to sequential addresses in turn so that as much of the block as possible is used up before performing an erase operation. For example, when programming groups of 16 bytes, the effective number of rewrites can be minimized by programming up to 128 groups before erasing them all in one operation. It is also advisable to retain data on the erasure endurance of each block and limit the number of erase operations to a certain number.
5. If an error occurs during block erase, attempt to execute the clear status register command, then execute the block erase command at least three times until the erase error does not occur.
6. Customers desiring program/erase failure rate information should contact their Renesas technical support representative.
7. The data hold time includes time that the power supply is off or the clock is not supplied.

**Table 5.40 Flash Memory (Data flash Block A to Block D) Electrical Characteristics**

Symbol	Parameter	Conditions	Standard			Unit
			Min.	Typ.	Max.	
—	Program/erase endurance <sup>(2)</sup>		10,000 <sup>(3)</sup>	—	—	times
—	Byte program time (program/erase endurance ≤ 1,000 times)		—	160	1500	μs
—	Byte program time (program/erase endurance > 1,000 times)		—	300	1500	μs
—	Block erase time (program/erase endurance ≤ 1,000 times)		—	0.2	1	s
—	Block erase time (program/erase endurance > 1,000 times)		—	0.3	1	s
t <sub>d</sub> (SR-SUS)	Time delay from suspend request until suspend		—	—	5 + CPU clock × 3 cycles	ms
—	Interval from erase start/restart until following suspend request		0	—	—	μs
—	Time from suspend until erase restart		—	—	30 + CPU clock × 1 cycle	μs
t <sub>d</sub> (CMDRST-READY)	Time from when command is forcibly stopped until reading is enabled		—	—	30 + CPU clock × 1 cycle	μs
—	Program, erase voltage		2.7	—	5.5	V
—	Read voltage		1.8	—	5.5	V
—	Program, erase temperature		–20	—	85	°C
—	Data hold time <sup>(7)</sup>	Ambient temperature = 55 °C	20	—	—	year

**Notes:**

1. V<sub>CC</sub> = 2.7 to 5.5 V and T<sub>opr</sub> = –20 to 85 °C (N version), unless otherwise specified.
2. Definition of programming/erasure endurance  
The programming and erasure endurance is defined on a per-block basis.  
If the programming and erasure endurance is n (n = 10,000), each block can be erased n times. For example, if 1,024 1-byte writes are performed to different addresses in block A, a 1 Kbyte block, and then the block is erased, the programming/erasure endurance still stands at one. However, the same address must not be programmed more than once per erase operation (overwriting prohibited).
3. Endurance to guarantee all electrical characteristics after program and erase. (1 to Min. value can be guaranteed.)
4. In a system that executes multiple programming operations, the actual erasure count can be reduced by writing to sequential addresses in turn so that as much of the block as possible is used up before performing an erase operation. For example, when programming groups of 16 bytes, the effective number of rewrites can be minimized by programming up to 128 groups before erasing them all in one operation. In addition, averaging the erasure endurance between blocks A to D can further reduce the actual erasure endurance. It is also advisable to retain data on the erasure endurance of each block and limit the number of erase operations to a certain number.
5. If an error occurs during block erase, attempt to execute the clear status register command, then execute the block erase command at least three times until the erase error does not occur.
6. Customers desiring program/erase failure rate information should contact their Renesas technical support representative.
7. The data hold time includes time that the power supply is off or the clock is not supplied.

**Figure 5.25 Time delay until Suspend**

**Table 5.48 Timing Requirements of Synchronous Serial Communication Unit (SSU)**

Symbol	Parameter		Conditions	Standard			Unit
				Min.	Typ.	Max.	
tsucyc	SSCK clock cycle time			4	—	—	tcyc (2)
tHI	SSCK clock "H" width			0.4	—	0.6	tsucyc
tLO	SSCK clock "L" width			0.4	—	0.6	tsucyc
tRISE	SSCK clock rising time	Master		—	—	1	tcyc (2)
		Slave		—	—	1	μs
tFALL	SSCK clock falling time	Master		—	—	1	tcyc (2)
		Slave		—	—	1	μs
tsu	SSO, SSI data input setup time			100	—	—	ns
tH	SSO, SSI data input hold time			1	—	—	tcyc (2)
tLEAD	SCS setup time	Slave		1tcyc + 50	—	—	ns
tLAG	SCS hold time	Slave		1tcyc + 50	—	—	ns
tOD	SSO, SSI data output delay time			—	—	1	tcyc (2)
tsa	SSI slave access time		2.7 V ≤ Vcc ≤ 5.5 V	—	—	1.5tcyc + 100	ns
			1.8 V ≤ Vcc < 2.7 V	—	—	1.5tcyc + 200	ns
tor	SSI slave out open time		2.7 V ≤ Vcc ≤ 5.5 V	—	—	1.5tcyc + 100	ns
			1.8 V ≤ Vcc < 2.7 V	—	—	1.5tcyc + 200	ns

Notes:

1. Vcc = 1.8 to 5.5 V, Vss = 0 V, and Topr = −20 to 85 °C (N version), unless otherwise specified.
2. 1tcyc = 1/f1(s)

**Table 5.56 Electrical Characteristics (3) [ $2.7\text{ V} \leq V_{CC} < 4.2\text{ V}$ ]**

Symbol	Parameter		Condition		Standard			Unit
					Min.	Typ.	Max.	
V <sub>OH</sub>	Output "H" voltage	Other than XOUT	Drive capacity High	I <sub>OH</sub> = -5 mA	V <sub>CC</sub> - 0.5	—	V <sub>CC</sub>	V
			Drive capacity Low	I <sub>OH</sub> = -1 mA	V <sub>CC</sub> - 0.5	—	V <sub>CC</sub>	V
		XOUT		I <sub>OH</sub> = -200 $\mu$ A	1.0	—	V <sub>CC</sub>	V
V <sub>OL</sub>	Output "L" voltage	Other than XOUT	Drive capacity High	I <sub>OL</sub> = 5 mA	—	—	0.5	V
			Drive capacity Low	I <sub>OL</sub> = 1 mA	—	—	0.5	V
		XOUT		I <sub>OL</sub> = 200 $\mu$ A	—	—	0.5	V
V <sub>T+</sub> -V <sub>T-</sub>	Hysteresis	$\overline{\text{INT0}}, \overline{\text{INT1}}, \overline{\text{INT2}}, \overline{\text{INT3}}, \overline{\text{INT4}}, \overline{\text{K10}}, \overline{\text{K11}}, \overline{\text{K12}}, \overline{\text{K13}}, \overline{\text{TRAIO}}, \overline{\text{TRCIOA}}, \overline{\text{TRCIOB}}, \overline{\text{TRCIOC}}, \overline{\text{TRCIOD}}, \overline{\text{USB_OVRCURA}}, \overline{\text{USB_VBUS}}, \overline{\text{TRCTRG}}, \overline{\text{TRCCLK}}, \overline{\text{ADTRG}}, \overline{\text{RXD0}}, \overline{\text{RXD1}}, \overline{\text{RXD2}}, \overline{\text{RXD3}}, \overline{\text{CLK0}}, \overline{\text{CLK1}}, \overline{\text{CLK2}}, \overline{\text{CLK3}}, \overline{\text{CTS2}}, \overline{\text{SSI}}, \overline{\text{SCL}}, \overline{\text{SDA}}, \overline{\text{SSO}}, \overline{\text{SSCK}}, \overline{\text{SCS}}$	V <sub>CC</sub> = 3.0 V		0.1	0.4	—	V
		$\overline{\text{RESET}}$	V <sub>CC</sub> = 3.0 V		0.1	0.5	—	V
I <sub>IH</sub>	Input "H" current		V <sub>I</sub> = 3 V, V <sub>CC</sub> = 3.0 V		—	—	4.0	$\mu$ A
I <sub>IL</sub>	Input "L" current		V <sub>I</sub> = 0 V, V <sub>CC</sub> = 3.0 V		—	—	-4.0	$\mu$ A
R <sub>PULLUP</sub>	Pull-up resistance		V <sub>I</sub> = 0 V, V <sub>CC</sub> = 3.0 V		42	84	168	k $\Omega$
R <sub>fXIN</sub>	Feedback resistance	XIN			—	0.3	—	M $\Omega$
V <sub>RAM</sub>	RAM hold voltage		During stop mode		1.8	—	—	V

Note:

1.  $2.7\text{ V} \leq V_{CC} < 4.2\text{ V}$ , T<sub>opr</sub> = -20 to 85 °C (N version), and f(XIN) = 10 MHz, unless otherwise specified.
2.  $3.0\text{ V} \leq V_{CC} < 3.6\text{ V}$  for the USB associated pins.

**Table 5.57 Electrical Characteristics (4) [ $2.7\text{ V} \leq V_{CC} < 3.3\text{ V}$ ]**  
**( $T_{opr} = -20\text{ to }85\text{ }^{\circ}\text{C}$  (N version), unless otherwise specified.)**

Symbol	Parameter	Condition	Standard			Unit
			Min.	Typ.	Max.	
I <sub>CC</sub>	Power supply current ( $V_{CC} = 2.7\text{ to }3.3\text{ V}$ ) Single-chip mode, output pins are open, other pins are V <sub>SS</sub>	High-speed clock mode	—	3.5	10	mA
				1.5	7.5	mA
		High-speed on-chip oscillator mode	—	7.0	15	mA
			—	3.0	—	mA
			—	4.0	—	mA
			—	1.5	—	mA
			—	1	—	mA
			—	90	390	μA
		Wait mode	—	15	90	μA
			—	4	80	μA
			—	3.5	—	μA
		Stop mode	—	2.0	5.0	μA
			—	15	—	μA